FORM PTO-1449 (Colb)	ATTY DOCKET NO	SERIAL NUMBER
	F-013596-8	09/829,435
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Yoel ARIELI, et al	
	FILING DATE April 9, 2001	GROUP ART UNIT 2877

U S PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO	DATE	NAME	CLASS	SUB	FILING DATE
	AA	5.969.858	Oct 1999	Ishiwata, et al	359	386	
	AB	5.969.853	Oct 1999	Takaoka	359	370	
	AC	5.936.253	Aug 1999	Sugaya	250	548	
	AD	5.870.191	Feb 1999	Shirley, et al	345	356	
	AE	5.814.815	Sep 1998	Matsumoto, et al	250	311	
	AF	5.751.475	May 1998	Ishiwata, et al	359	387	
	AG	5.619.372	Apr 1997	Hellmuth, et al	359	389	
	AH	5.600.440	Feb 1997	Bendall	356	345	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO	DATE	COUNTRY	CLASS	SUB	TRANS-LATION
	AI	JP 9230247	9/1997	Japan			
	AJ	JP 9179029	7/1997	Japan			
	AK	JP 8094936	4/1996	Japan			

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AL   Phillion D.W. "General Methods for Generating Phase-Shifting Interferometry Algorithms" Applied Optics Vol. 36, 8098 (1997)

AM   Plata M. "Stray-Light Problem in Phase Contrast Microscopy or Toward Highly Sensitive Phase Contrast Devices A review" Optical engineering Vol 32 3469 (1993)

EXAMINER   DATE CONSIDERED 12/16/03

EXAMINER   Initial if reference considered whether or not citation is in conformance with MPEP 609 Draw line through citation if not in conformance and not considered Include copy of this form with next communication to applicant

FORM PTO-1449 (Colb)	ATTY DOCKET NO	SERIAL NUMBER
	L-013396-8	09 829.435

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Yoel ARIELI, et al

	FILING DATE	GROUP ART UNIT
	April 9, 2001	2877

US PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO	DATE	NAME	CLASS	SUB	FILING DATE
ol	AA	5,159,474	Oct 1992	Franke, et al	359	29	
	AB	5,777,736	Jul 1998	Horton	356	346	
	AC	4,653,921	Mar 1987	Kwon	356	353	
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO	DATE	COUNTRY	CLASS	SUB	TRANSLATION
GM	AF	EP 0 555 099	8/1993	Europe			
GM	AG	GB 2,315,700	2/1998	Great Britain			
	AH						

OTHER ART (Including Author, Title, Pertinent Pages, Etc.)

vb	AI	Golden L J "Zernike Test I Analytical Aspects" Applied Optics, Vol. 16, 205 (1977)
vl	AJ	Bruning J H, et al "Digital Wavefront Measuring Interferometry for Testing Optical Surfaces and Lenses" Applied Optics, Vol. 13, 2693 (1974)
	AK	
	AL	

EXAMINER _(signature)_   DATE CONSIDERED 11/16/03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 (Cont.)

ATTY DOCKET NO
L-013396-8

SERIAL NUMBER
09/829,435

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANTS' INFORMATION
STATEMENT

APPLICANT
Yoel ARIELI, et al

FILING DATE
April 9, 2001

GROUP ART UNIT
2877

US PATENT DOCUMENTS

Examiners Initials		DOCUMENT NO	DATE	NAME	CLASS	SUB	FILING DATE
	AA	5,471,303	Nov 1995	Ai, et al	356	357	
	AB	5,446,540	Aug 1995	Lin	356	345	
	AC	5,235,587	Apr 1993	Bearden, et al	369	106	
	AD	4,407,569	Oct 1983	Piller, et al	350	509	
	AE	4,190,366	Feb 1980	Doyle	356	346	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO	DATE	COUNTRY	CLASS	SUB	TRANS-LATION
	AF	JP 7261089	10/1995	Japan			
	AG	JP 7225341	8/1995	Japan			
	AH	JP 6186504	7/1994	Japan			

OTHER ART (Including Author, Title, Pertinent Pages, Etc.)

AI   Noda T and Kawata S, "Separation of Phase and Absorption Images in Phase-Contrast Microscopy", Journal of the Optical Society of America A, Vol 9, 924 (1992)

AJ   Creath K, "Phase Measurement Interferometry Techniques", Progress in Optics XXVI, 348 (1988)

AK   Greivenkamp J E, "Generalized Data Reduction for heterodyne Interferometry", Optical Engineering, Vol 23, 354 (1984)

AL   Morgan C J, "Least Squares Estimation in Phase-Measurement Interferometry", Optics Letters, Vol 7, 368 (1982)

EXAMINER   DATE CONSIDERED   4/16/03